

<b>Complaint Counsel's Proposed List Of Rambus Expert Testimony To Be Covered In Rebuttal</b>	<b>Pages In Professor Jacob's Trial Testimony Where He Testified On The Topics In Question</b>
<b>LEE/RYAN/JACOBS TOPICS</b>	
<p>1. it is reasonable to assume that a first-tier manufacturer would run only 20 million units of a product iteration (Geilhufe, Tr. 9562:10-9563:4; 9725:1-9726:23)</p>	<p>This issue was not addressed in Professor Jacob's trial testimony. However, because it was not addressed in his initial or rebuttal report, he may not now testify regarding the issue.</p>

2. use of fixed CAS latency parts is difficult and costly because (a) based on all options contained in the JEDEC standard as adopted (and not on industry usage or practice), 3 separate parts would be required (Geilhufe, Tr. 9578:10-23, Tr. 9682:20-9683:2)

See below at pp. 12-13 (Jacob point 1) for Professor Jacob's testimony on the fixed CAS latency alternative. , Tec4i1Tj 00371

**EXHIBIT C**

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(e) it would add expense due to decreased die yield (Geilhufe, Tr. 9577:1-9578:9)	
<p>3. use of fixed burst length parts is difficult and costly because</p> <p>(a) based on all options in the JEDEC standard as adopted (and not on industry usage or practice), it would require 4 separate parts (Geilhufe, Tr. 9594:25-9595:3)</p>	<p>Professor Jacob testified extensively about the alternatives of using fixed CAS latency and/or burst length extensively in his direct examination (Tr. 5371:2 – 5378:16, 5398:25 – 5403:1). In this testimony he attempted to respond to various of the disadvantages raised by Dr. Soderman and Mr. Geilhufe. For example, with respect to the added expense of fixed CAS latency, Professor Jacob testified as follows:</p> <p><u>Tr. 5376:5 – 5377:11 (Jacob):</u></p> <p>Q. Now, in comparison with use of a mode register to program CAS latency, what advantages, if any, would have been realized by using fixed CAS latency in the 1991 to 1996 time period?</p> <p>A. It would be potentially a simpler design. Certainly you don't have a mode register, so that's a simpler mechanism. You potentially would have fewer testing stages, and again, that depends on where you decide to fix the CAS latency. For example, if you fix it earlier in the design stage, you don't actually have to test the fabricated part for multiple CAS latencies. So the test costs and design costs can go down.</p> <p>Q. You referred to a simpler design. Why do you include that as among the advantages?</p> <p>A. Well, because you don't have to build and test a mode register.</p> <p>Q. Are you familiar with the term "die size"?</p> <p>A. Yes, I am.</p> <p>Q. And what does "die size" mean?</p> <p>A. Thank you.</p> <p>It's the size of the semiconductor die. And the cost of manufacturing goes roughly with the area to the third power, the area of this semiconductor part, so if you have a part that is 1 percent larger, it's approximately 3 percent more expensive to manufacture. So for example, if you eliminate a mode register, you eliminate some of the size</p>



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	<p>Q. In particular, it stores the burst length; is that right?</p> <p>A. Yes.</p> <p>Q. And it stores the burst type; right?</p> <p>A. Yes.</p> <p>Q. And in DDR SDRAMs they expand the use of the mode register and they store other things in the mode register; right?</p> <p>A. I believe so.</p> <p>Q. And in DDR-II SDRAMs they're expanding the use of the mode register yet further again, storing even more things in the mode register; right?</p> <p>A. I'm not certain about that.</p> <p>Q. You don't know one way or the other?</p> <p>A. I don't have the DDR-II spec in front of me and I have not consulted it recently, so I don't know offhand.</p> <p>Q. If you just remove the programmable CAS latency feature and went to fixed latency, you would still need the mode register for these various other purposes; correct?</p> <p>A. If you were to retain those features, you would require the portion of the mode register used to implement those features and you could eliminate the portion of the mode register and the portion of the control logic that would be used to implement the CAS latency feature.</p>
<p>6. (a) electrically blown fuses and anti-fuses are not reliable (Soderman, Tr. 9356:18-9357:2)</p>	<p>This precise issue was raised in Professor Jacob's cross-examination. Complaint Counsel could have followed up to the extent necessary on re-direct.</p> <p><u>Tr. 5596:23-25 (Jacob cross):</u></p> <p>Q. Now, you know that electrical fuses are not as reliable as laser-blown fuses; right?</p> <p>A. No, I do not know that.</p>
<p>(b) based on a survey of "maybe 50" out of "hundreds" of data sheets, only about 2 out of 50 SDRAMs appear to incorporate electrically blown fuses (Soderman, Tr.</p>	

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9357:3-9358:1)	
(c) anti-fuse technology is not generally available in DRAMs (Geilhufe, Tr. 9582:20-9583:19; Tr. 9732:11-9734:21)	<p>This issue was raised during Professor Jacob's direct examination and was followed up during cross-examination. Complaint Counsel could have followed up further during re-direct to the extent necessary.</p> <p><u>Tr. 5381:21 – 5382:1 (Jacob):</u></p> <p>Q. Now, the fuses that are used in synchronous DRAMs today, are they laser blown or electrically blown or both or other?</p> <p>A. They are both. They are – some manufacturers use laser-blown fuses; other manufacturers use electrically blown fuses.</p> <p><u>Tr. 5595:21 – 5596:22 (Jacob – cross):</u></p> <p>Q. And you also mentioned that another type of fuse is an electrical fuse; right?</p> <p>A. An electrically blown fuse, correct.</p> <p>Q. And you said that some DRAM manufacturers are using electrically blown fuses; right?</p> <p>A. Yes, I did.</p> <p>Q. What DRAM manufacturers are those?</p> <p>A. I believe Infineon and Micron and possibly Hynix.</p> <p>Q. And do you know what parts they're using those electrical fuses in?</p> <p>A. I don't know the part numbers.</p> <p>Q. Do you know how many parts Micron is using electrical fuses in?</p> <p>A. I believe a substantial number.</p> <p>Q. Is Micron using the electrical fuses in all of its DRAM products?</p> <p>A. I don't know if it's all, but I believe it's a substantial number. That's my understanding.</p> <p>Q. Do you know how many?</p> <p>A. A substantial number of the parts that they create.</p> <p>Q. Do you know what percentage?</p> <p>A. No.</p> <p>Q. Do you know what percentage of Infineon's parts use electrical fuses?</p>

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**Pages In Professor Jacob's Trial Testimony Where He  
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A.

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Tr. 9609:17-9610:5)

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- Q. Do you know how much a standard PLL costs?
- A. I believe it's generally around \$1.
- Q. And in light of these modifications, would the PLL for Kentron be cheaper o

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<p>10. SLDRAM was unable to design a high speed DRAM using Vernier circuitry, without an on-chip DLL (Soderman, Tr. 9412:22-9415:9)</p>	<p>This precise issue was raised in Professor Jacob's cross-examination. Complaint Counsel could have followed up to the extent necessary on re-direct. Since Professor Jacob's testimony preceded that of Terry Lee, Complaint Counsel could have also questioned Mr. Lee about this issue once it had been raised.</p> <p><u>Tr. 5618:3 – 5621:18 (Jacob – cross):</u></p> <p>Q. Now, one of the alternatives that you mentioned yesterday to this idea of using an on-chip DLL was a vernier circuit; right?</p> <p>A. Yes.</p> <p>Q. And you're aware, correct, that the SLDRAM chip designed by SyncLink used a vernier?</p> <p>A. Yes, I am.</p> <p>Q. And isn't it also true that the SLDRAM chip used an on-chip DLL in addition to the vernier in order to make the timing more accurate?</p> <p>A. I'm not sure what you mean by making the timing more accurate. The DLL was not used to capture data. That's not the timing that it was making more accurate. So I don't know what you're getting at.</p> <p>Q. Well, you testified in your deposition that the purpose of that DLL on top of the vernier in SyncLink SLDRAMs was to make the timing more accurate, didn't you?</p> <p>A. I didn't say it was on top of the vernier.</p> <p>Q. Could we turn to your deposition, at page 167. And on that page, we're discussing a conversation that you had with Mr. Terry Lee of Micron about the use of verniers and DLLs and SLDRAMs. Do you see that?</p> <p>A. Yes, I do.</p> <p>Q. And you're describing what Mr. Lee told you in your response there; right?</p> <p>A. I am describing my understanding of the way the vernier and the DLL are used in the SLDRAM work.</p> <p>Q. And in the sentence of your response, lengthy response that begins at line 17, you state, "And so this static calculation was done, and the vernier was set in each of the DRAMs, and that the DLL was used to make that timing a little bit more accurate"; correct?</p>





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	<p>DC-type interface, is much less expensive than adding, for instance, what they call a high-speed pin, a data-type pin.</p> <p><u>Tr. 5391:12 - 5392:25 (Jacob):</u></p> <p>Q. Now, what, if any, would have been the advantages had JEDEC chosen to explicitly identify CAS latency in the read command rather than using a mode register to program CAS latency?</p> <p>A. The advantage would be that you would eliminate the mode register and the circuitry required to decode special commands and put that information into the mode register, so it would make the part potentially smaller and simpler.</p> <p>Q. And would that have had any implication for cost?</p> <p>A. Yes. That potentially would reduce the cost of the part.</p> <p>Q. What, if any, would have been the disadvantages had JEDEC chose to explicitly identify CAS latency in the read command rather than using a mode register?</p> <p>A. The disadvantage would be that it would make the decoding logic on the DRAM more complex because you would have these additional commands that would need to be decoded, so that would make the part more complex, so you'd have a trade-off there. And if, for example, there were certain combinations that you had to support and you didn't want to redefine, for example, the DQ mask pins in the way I've described, it might require an additional pin.</p> <p>Q. Focusing on the use of existing pins for the moment, you mentioned that it might require more complex decode circuitry?</p> <p>A. Yes.</p> <p>Q. How significant would that be?</p> <p>A. Not very significant. It would be on the order of the complexity that you're removing by not having to decode the initialization commands.</p> <p>Q. In other words, on the order of the complexity that would be removed by taking off the mode register?</p> <p>A. Absolutely.</p>

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<p>3. Design of a burst terminate command is fully viable.</p>	<p>Professor Jacob testified extensively about the viability of suing a burst terminate command to set burst length in his direct testimony. (Tr. 5408:20 – 5411:12) In this testimony, he specifically responded to Dr. Soderman's criticism that this alternative would have led to inefficiencies:</p> <p><u>Tr. 5411:1-12 (Jacob):</u></p> <p>Q. Now, what, if any, would have been the disadvantages had JEDEC chosen to use a long burst length with a burst terminate command rather than programming burst length through the mode register?</p> <p>A. You potentially could run into inefficiencies on the bus depending upon how you -- depending upon how the memory controller handles those situations where you want to terminate the burst down to 4 from 8.</p> <p>Q. How significant a disadvantage would that have been?</p> <p>A. I don't believe it would have been very significant.</p>
<p>4. Using a faster single-edge clock does not require conducting other operations at a faster speed.</p>	<p>Professor Jacob testified extensively about the alternative of using a faster single-edge clock as an alternative to dual-edge clocking in his direct testimony. (Tr. 5433:8 – 5435:3) In this testimony, he specifically addressed whether, in his opinion, this would require conducting other operations at a faster speed:</p> <p><u>Tr. 5434:21 – 5435:7 (Jacob):</u></p> <p>Q. This example, would this require any increase in the speed or frequency of command signals?</p> <p>A. No, it would not. You would still send your command and addresses at the same rates that you send them now. The only thing that would change would be the data rate and it would be similar to or, rather -- I'm sorry. The only thing that would change would be the clock frequency that accompanies your data transmission. Your data rates would be the same as in DDR parts of today, but your clock frequency would be twice what it is.</p>
<p>5. Using a faster</p>	<p>In his testimony about using a faster single-edged clock,</p>

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<p>single-edged clock would not involve significant engineering difficulties (including use of on-DIMM clock circuitry or an on-DIMM PLL/DLL).</p>	<p>Professor Jacob also addressed the engineering difficulties involved:</p> <p><u>Tr. 5434:8 – 5435:3 (Jacob):</u></p> <p>Q. Now, what, if any, would have been the advantages of running a single-edged clock at twice the frequency rather than using a dual-edged clock?</p> <p>A. The advantages include the fact that you have the single-edged clock versus a dual-edged clock, meaning that the edge rates need not be symmetric, the duty cycle need not be 50 percent, and it gives you those extra edges per data packet that are not present in a dual-edged clocking scheme, you have an edge to transmit data as well as another edge to receive data, whereas in a dual-edged clocking scheme you only have an edge to drive data or you have an edge to receive data, but you don't have both.</p> <p>Q. Now, what, if any, would have been the disadvantages had JEDEC chosen to double the frequency of a single-edged clock rather than using a dual-edged clock?</p> <p>A. You have a clock signal that is transitioning at twice the rate of present, of present systems, which means it would be burning twice as much power as present systems.</p>
<p>6. The proposed alternatives to dual-edge clocking do not involve using both edges of the clock.</p>	<p>Professor Jacob testified generally that his proposed alternatives were, in fact, <i>alternatives</i> to dual-edge clocking – i.e. that they do not involve using both edges of the clock.</p>